

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/700,498	<b>Applicant(s)/Patent under Reexamination</b> OBAYASHI ET AL.
	<b>Examiner</b> Thomas R. Hannon	<b>Art Unit</b> 3682

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner